

**Amendments to the Abstract:**

Please replace the abstract with the following replacement Abstract:

Methods and systems for improving repairing efficiency in non-volatile memory. Repairing data may be read from an information array associated with the non-volatile memory. The repairing data is generally read to a volatile latch associated with the non-volatile memory. An error correction coding circuit (ECC) circuit can be enabled during reading of the repairing data ~~to thereby identify and repair~~ for identifying and repairing defective columns or rows associated with the non-volatile memory, despite errors in the repairing data read out ~~regardless of the corruption of the columns.~~